



ELECTRICAL CHARACTERISTICS ( $T_j = 25\text{ }^\circ\text{C}$ )

Symbol	Item	Conditions	Min.	Typ.	Max.	Units	
$I_{CES}$	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA	
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=10mA, V_{CE}=10V$	5	6	7	V	
$I_{GES}$	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	0.5	$\mu A$	
$V_{CE(sat)}$	Collector to emitter saturation voltage ④	$T_j=25\text{ }^\circ\text{C}$   $I_C=100A$	—	5.0	6.5	V	A
		$T_j=125\text{ }^\circ\text{C}$   $V_{GE}=15V$	—	5.0	—		
$C_{ies}$	Input capacitance	$V_{CE}=10V$	—	—	16	nF	
$C_{oes}$	Output capacitance	$V_{GE}=0V$	—	—	1.3		
$C_{res}$	Reverse transfer capacitance		—	—	0.3		
$Q_G$	Total gate charge	$V_{CC}=600V, I_C=100A, V_{GE}=15V$	—	450	—	nC	
$t_d(on)$	Turn-on delay time	$V_{CC}=600V, I_C=100A$	—	—	100	ns	A
$t_r$	Turn-on rise time	$V_{GE1}=V_{GE2}=15V$	—	—	50		
$t_d(off)$	Turn-off delay time	$R_G=3.1\Omega$ , Inductive load	—	—	250		
$t_f$	Turn-off fall time	switching operation	—	—	150		
$t_{rr}$ ①	Reverse recovery time	$I_E=100A$	—	—	150		
$Q_{rr}$ ①	Reverse recovery charge		—	5.0	—	$\mu C$	
$V_{EC}$ ①	Emitter-collector voltage	$I_E=100A, V_{GE}=0V$	—	—	3.5	V	
$R_{th(j-c)Q}$	Thermal resistance	IGBT part (1/2 module)	—	—	0.22	$^\circ\text{C/W}$	A
$R_{th(j-c)R}$		FWDi part(1/2 module)	—	—	0.47		
$R_{th(c-f)}$	Contact thermal resistance	Case to fin,Thermal compound Applied (1/2module) *2	—	0.07	—		
$R_{th(j-c')Q}$	Thermal resistance *4	IGBT part (1/2 module)	—	—	$0.17^{*3}$		A
$R_{th(j-c')R}$		FWDi part(1/2 module)	—	—	$0.29^{*3}$		
$R_G$	External gate resistance		3.1	—	31	$\Omega$	

\*1:  $T_c$  measured point is shown in page OUTLINE DRAWING.

\*2: Typical value is measured by using Shin-etsu Silicone "G-746".

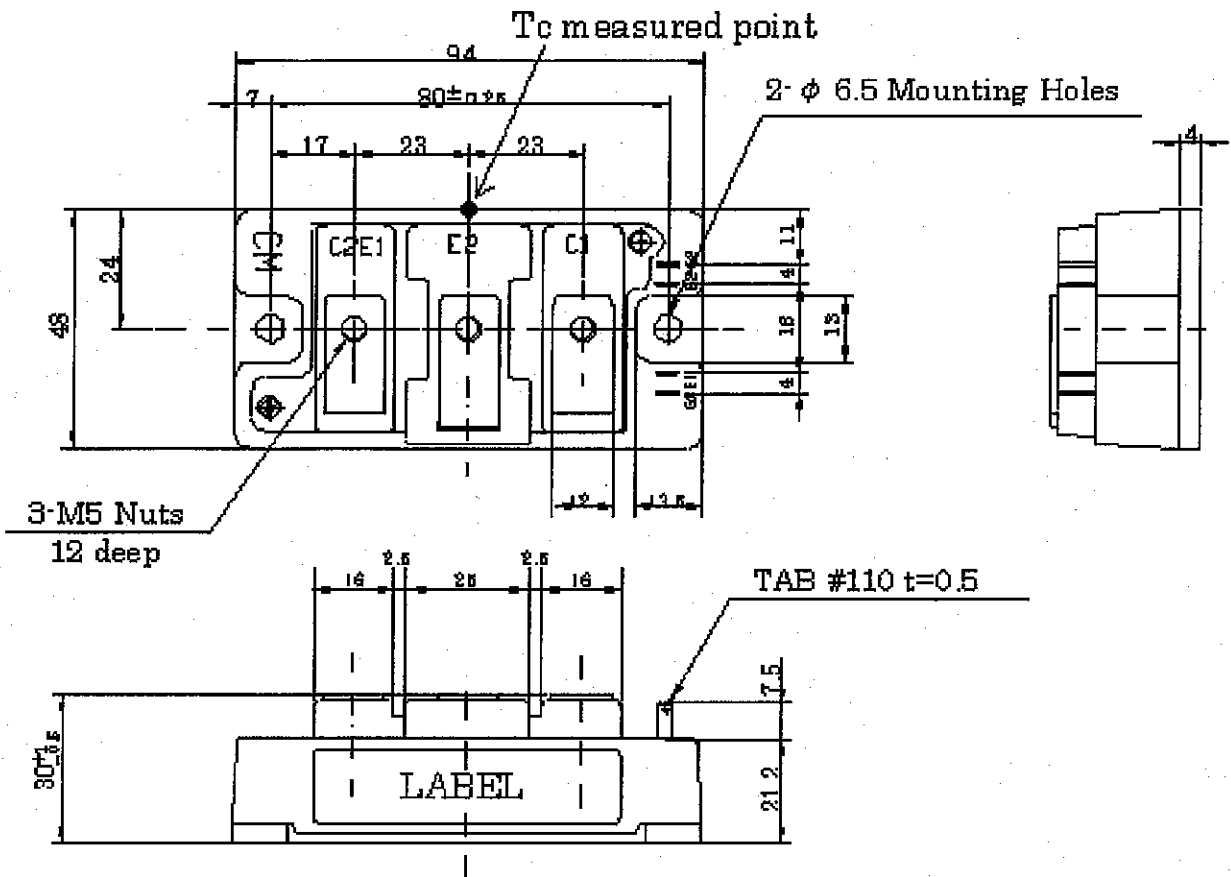
\*3: If you use this value,  $R_{th(f-a)}$  should be measured just under the chips.

\*4:  $T_c'$  measured point is just under the chips.

- ①  $I_E, V_{EC}, t_{rr}, Q_{rr}$  &  $di/dt$  represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).
- ② Pulse width and repetition rate should be such that the device junction temp. ( $T_j$ ) dose not exceed  $T_{jmax}$  rating.
- ③ Junction temperature ( $T_j$ ) should not increase beyond  $150^\circ\text{C}$ .
- ④ Pulse width and repetition rate should be such as to cause negligle temperature rise.
- ⑤ No short circuit capability is designed.

OUTLINE DRAWING

Dimensions in mm



CIRCUIT DIAGRAM

